P30309.A04

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

: Makoto KUROSAWA et al. Applicants

Group Art Unit: 2831

Appln. No. : 10/597,415

Examiner: Nguyen, Hoai-An D

(U.S. National Stage of PCT/JP2005/000933)

I.A. Filed

: January 19, 2005

Confirmation No.: 1744

For

: PHASE MEASUREMENT DEVICE, METHOD, PROGRAM, AND

RECORDING MEDIUM

COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE

Commissioner for Patents U.S. Patent and Trademark Office Customer Service Window, Mail Stop Issue Fee Randolph Building 401 Dulany Street Alexandria VA 22314

Sir:

In response to the Notice of Allowability, mailed by the U.S. Patent and Trademark Office on September 22, 2008 and to the Statement of Reasons for Allowance attached thereto, Applicants wish to clarify the record with respect to the basis for the patentability of claims in the present application. In this regard, while Applicants do not disagree with the Examiner's indication of allowability, Applicants submit that each of the claims in the present application recite a combination of features, and that the basis for patentability of each of these claims is based on the combination of features recited therein.

Should there be any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

> Respectfully submitted, Makoto KUROSAWA et al.

Bruce H. Bernstein

Reg. Nb. 29,027

James K. Moore, Jr. Reg. No. 56,272

November 3, 2008 GREENBLUM & BERNSTEIN, P.L.C. 1950 Roland Clarke Place Reston, VA 20191 (703) 716-1191